

FQP10N50CF / FQPF10N50CF 500V N-Channel MOSFET

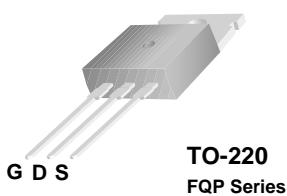
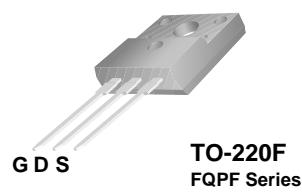
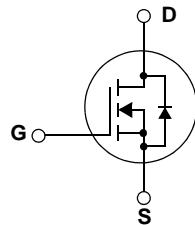
Features

- 10A, 500V, $R_{DS(on)} = 0.61 \Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 43 nC)
- Low Crss (typical 16pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Fast recovery body diode

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.


 TO-220
FQPF Series

 TO-220F
FQPF Series


Absolute Maximum Ratings

Symbol	Parameter	FQP10N50CF	FQPF10N50CF	Unit	
V_{DSS}	Drain-Source Voltage	500		V	
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	10	10*	A	
	- Continuous ($T_C = 100^\circ\text{C}$)	6.35	6.35*	A	
I_{DM}	Drain Current - Pulsed	(Note 1)	40	40*	A
V_{GSS}	Gate-Source voltage		± 30	V	
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	388	mJ	
I_{AR}	Avalanche Current	(Note 1)	10	A	
E_{AR}	Repetitive Avalanche Energy	(Note 1)	14.3	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	143	48	W	
	- Derate above 25°C	1.14	0.38	W/ $^\circ\text{C}$	
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$	
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	$^\circ\text{C}$	

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP10N50CF	FQPF10N50CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.87	2.58	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	$^\circ\text{C}/\text{W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP10N50CF	FQP10N50CF	TO-220	-	-	50
FQPF10N50CF	FQPF10N50CF	TO-220F	-	-	50

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$, $T_J = 25^\circ\text{C}$	500	--	--	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	--	0.5	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 500\text{V}$, $V_{\text{GS}} = 0\text{V}$	--	--	10	μA
		$V_{\text{DS}} = 400\text{V}$, $T_C = 125^\circ\text{C}$	--	--	100	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30\text{V}$, $V_{\text{DS}} = 0\text{V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30\text{V}$, $V_{\text{DS}} = 0\text{V}$	--	--	-100	nA
On Characteristics						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$	2.0	--	4.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10\text{V}$, $I_D = 5\text{A}$	--	0.5	0.61	Ω
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40\text{V}$, $I_D = 5\text{A}$	(Note 4)		15	--
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25\text{V}$, $V_{\text{GS}} = 0\text{V}$, $f = 1.0\text{MHz}$	--	1610	2096	pF
C_{oss}	Output Capacitance		--	177	230	pF
C_{rss}	Reverse Transfer Capacitance		--	16	24	pF
Switching Characteristics						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 250\text{V}$, $I_D = 10\text{A}$ $R_G = 25\Omega$	--	29	67	ns
t_r	Turn-On Rise Time		--	80	170	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	141	290	ns
t_f	Turn-Off Fall Time		--	80	165	ns
Q_g	Total Gate Charge	$V_{\text{DS}} = 400\text{V}$, $I_D = 10\text{A}$ $V_{\text{GS}} = 10\text{V}$	--	43	56	nC
Q_{gs}	Gate-Source Charge		--	7.5	--	nC
Q_{gd}	Gate-Drain Charge		--	18.5	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	10	--	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	40	--	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0\text{V}$, $I_S = 10\text{A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0\text{V}$, $I_S = 10\text{A}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	--	50	--	ns
Q_{rr}	Reverse Recovery Charge		--	0.1	--	μC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $L = 7\text{mH}$, $I_{AS} = 10\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 10\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

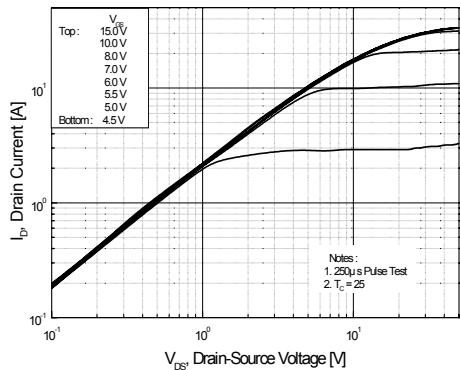


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

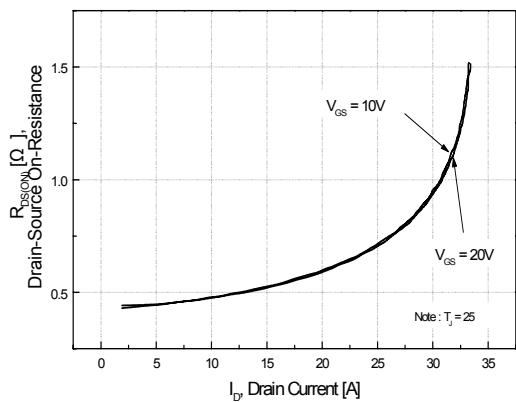


Figure 5. Capacitance Characteristics

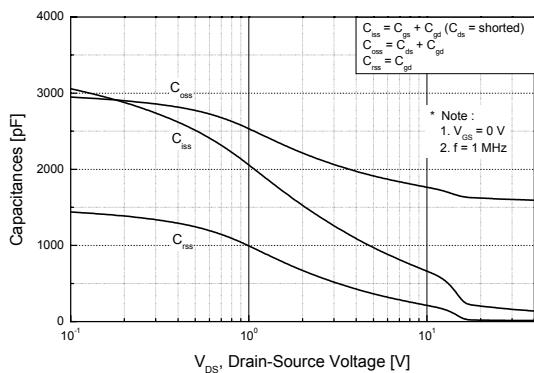


Figure 2. Transfer Characteristics

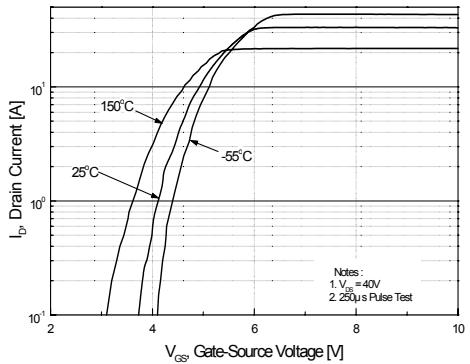


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

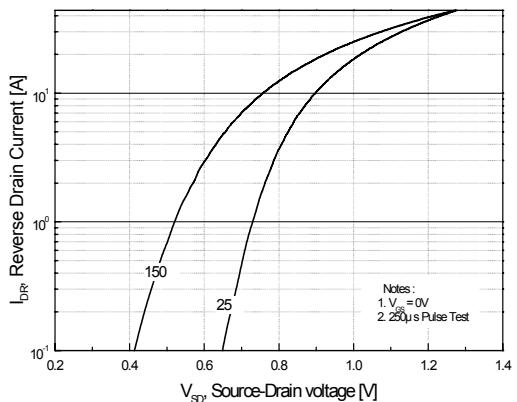
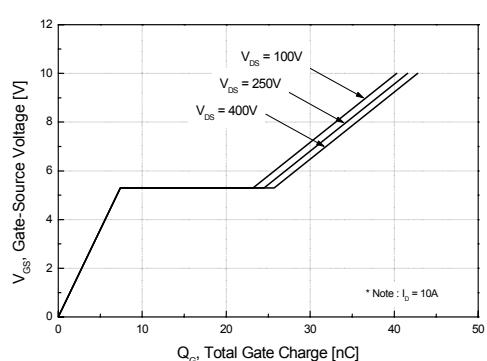


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

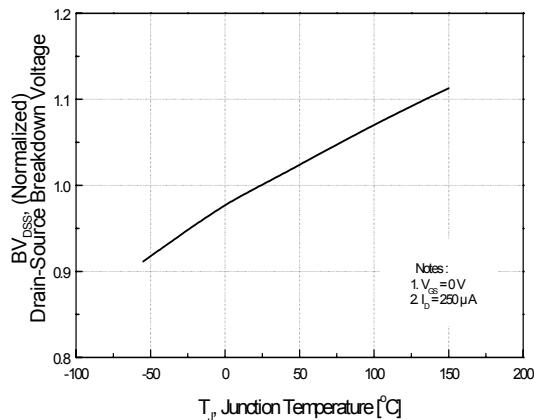


Figure 8. On-Resistance Variation vs. Temperature

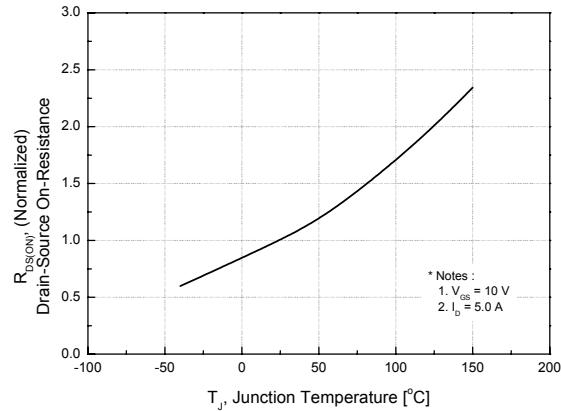


Figure 9-1. Maximum Safe Operating Area for FQP10N50CF

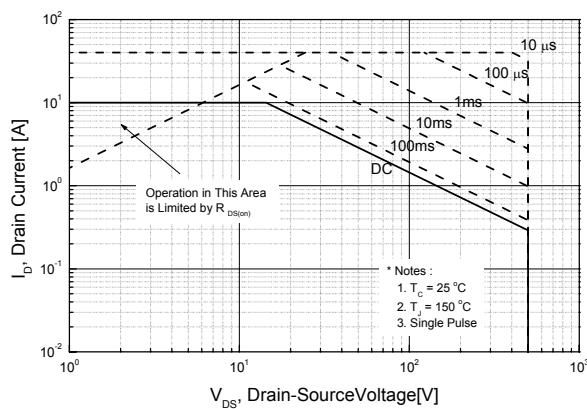


Figure 9-2. Maximum Safe Operating Area for FQPF10N50CF

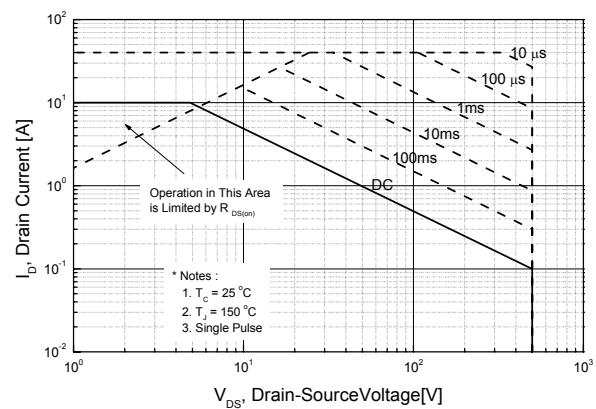
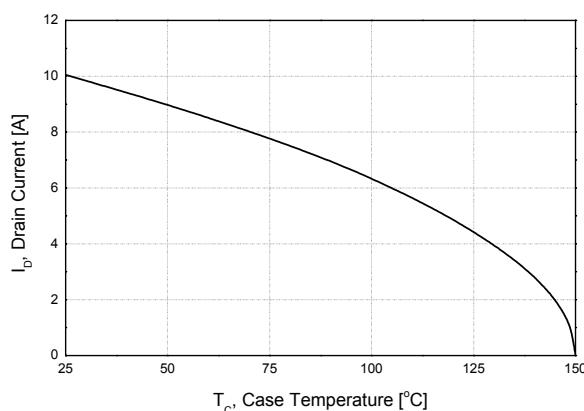


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FQP10N50CF

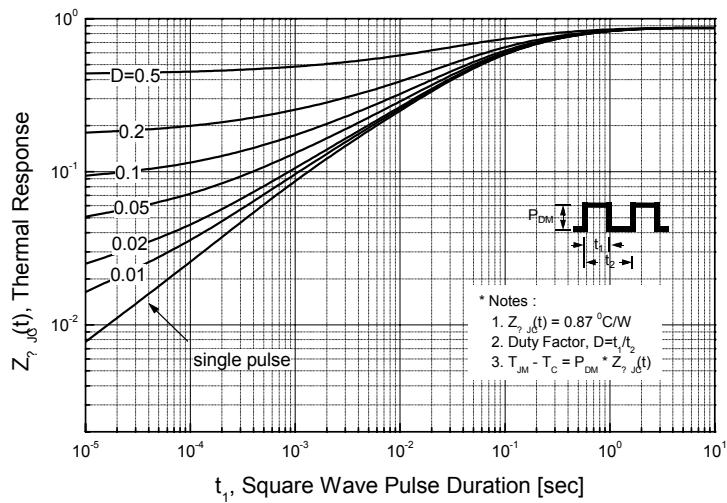
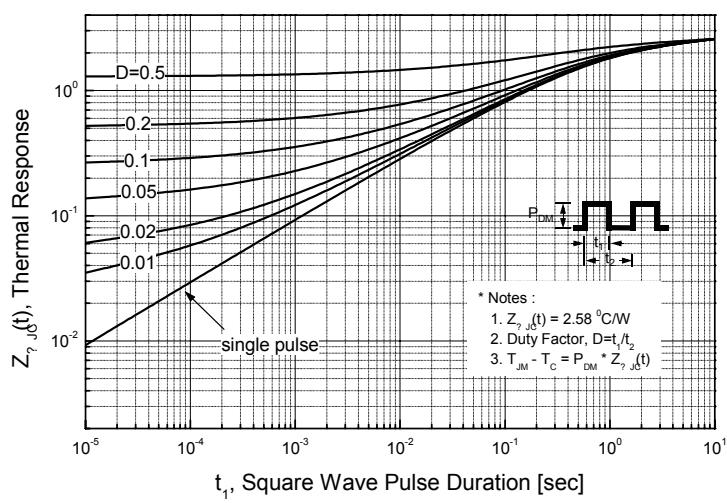
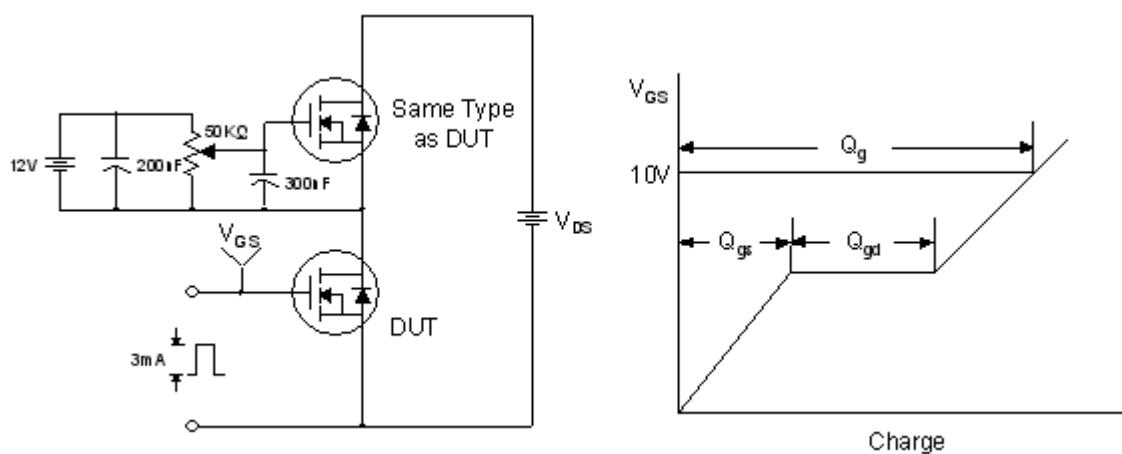


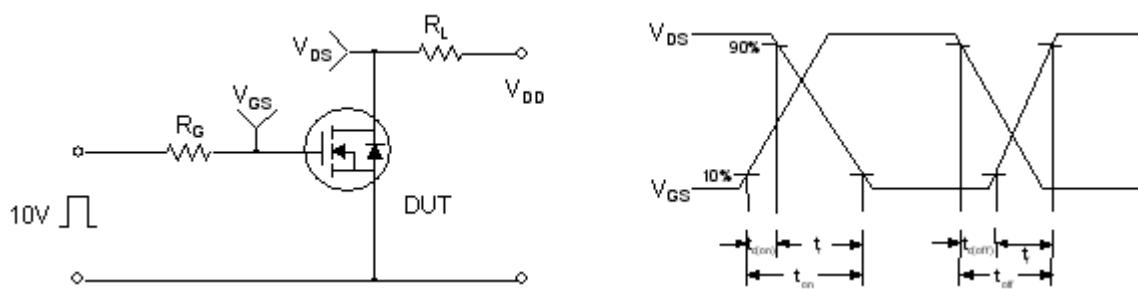
Figure 11-2. Transient Thermal Response Curve for FQPF10N50CF



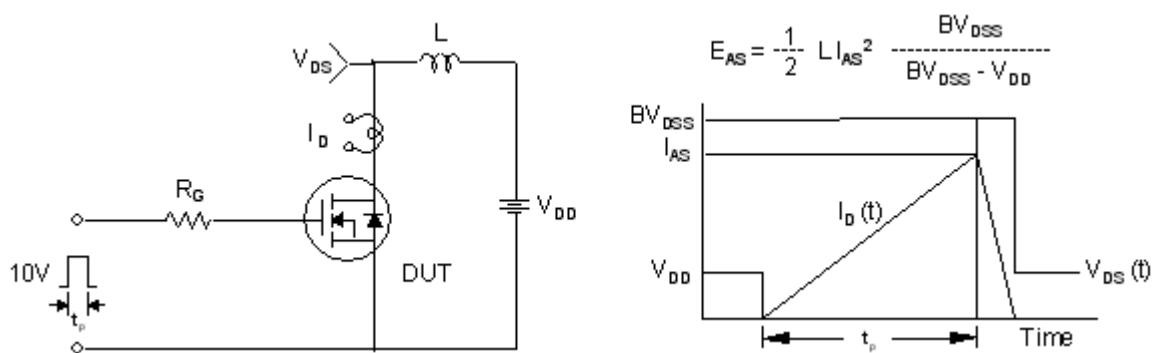
Gate Charge Test Circuit & Waveform



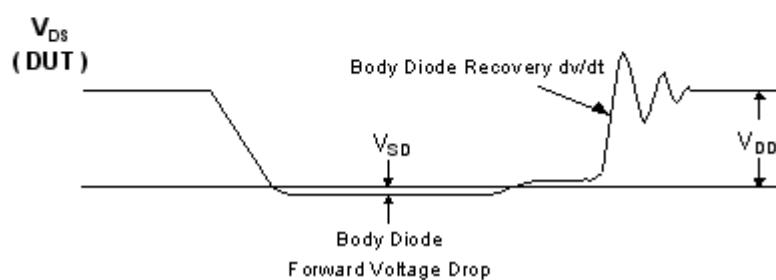
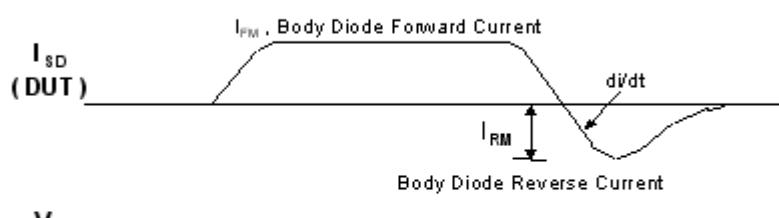
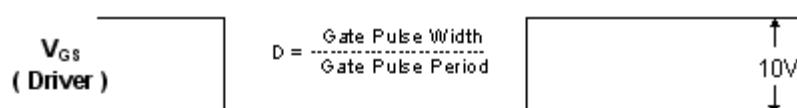
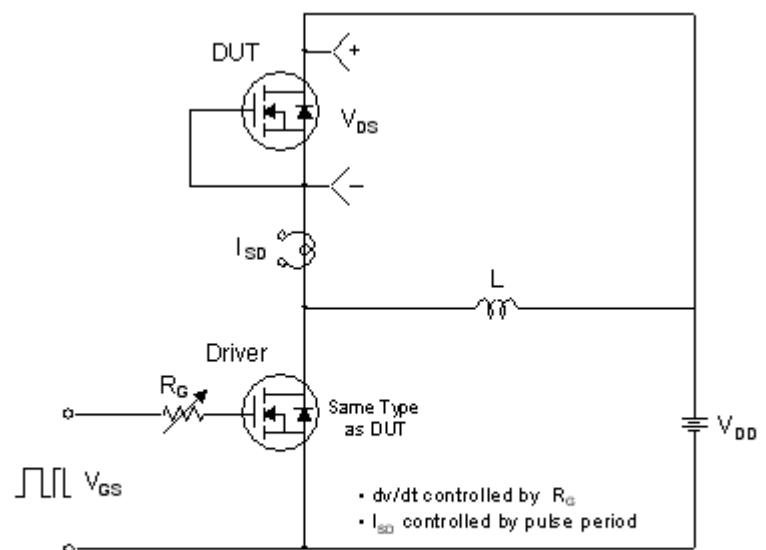
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

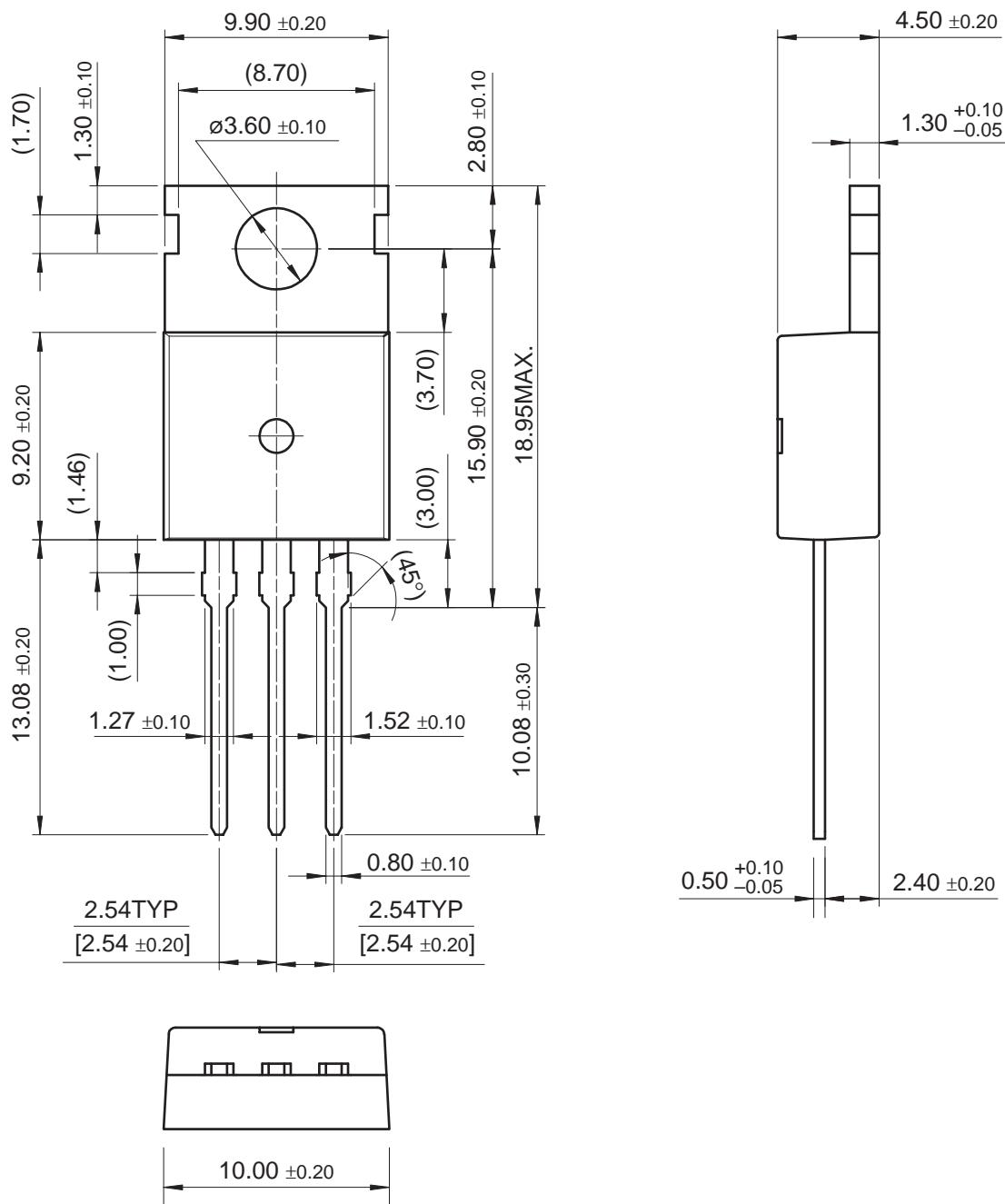


Peak Diode Recovery dv/dt Test Circuit & Waveforms

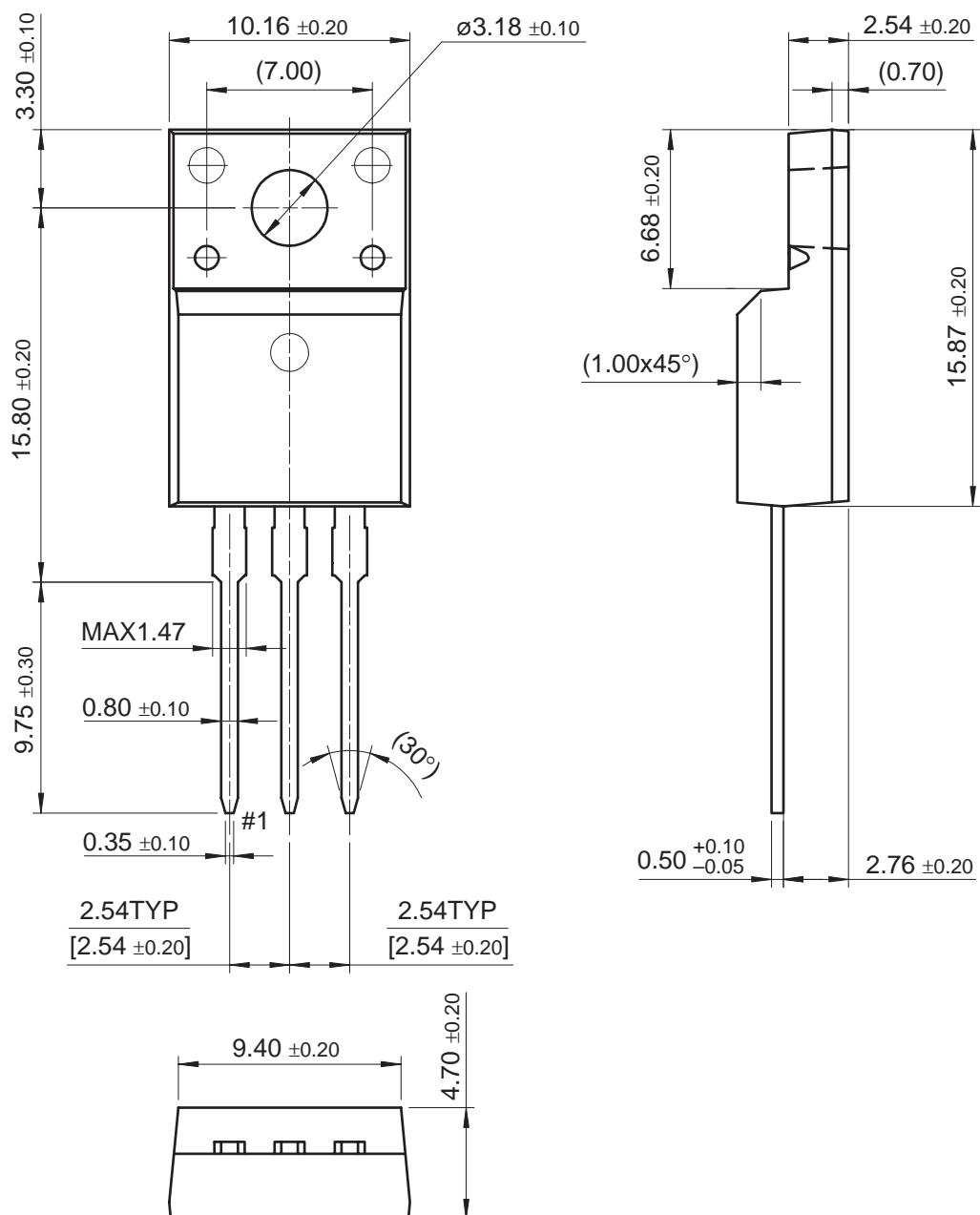


Mechanical Dimensions

TO-220



Dimensions in Millimeters

Mechanical Dimensions (Continued)**TO-220F**

Dimensions in Millimeters

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